

10/628,431

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Sheet	1	of	1	Attorney Docket Number	Q76579
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Examiner Initials*	Cite No.*	Document Number		Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document
		Number	Kind Code ² (if known)		
SAT		US 5 965 874		10/12/1999	THE FURUKAWA ELECTRIC CO., LTD Aso, et al.
		US 5 396 329		3/7/1995	BRITISH AEROSPACE PDC Kalawsky
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		US 5 166 752		11/24/1992	RUDOLPH RESEARCH CORPORATION Spanier, et al.
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6/27/07

FOREIGN PATENT DOCUMENTS

Examiner Initials*	Cite No.*	Foreign Patent Document			Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Translation ⁴
		Country Code ³	Number ⁴	Kind Code ⁵ (if known)			
SAT	DE	101 09 929	A1		11/22/2001	CARL ZEISS	
1	EP	0 439 127	A2		7/31/1991	HEWLETT PACKARD COMPANY	
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SAT	WO	03/028073	A1		4/3/2003	NIKON CORPORATION	Claims

NON PATENT LITERATURE DOCUMENTS

Examiner Initials*	Cite No.*	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city, and/or country where published.	Translation ⁴
SAT		"OPTICAL SHOP TESTING", EDITED BY DANIEL MALACARA, JOHN WILEY & SONS, INC., SECOND EDITION, PAGES 112-113, 1992, USA.	
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Examiner Signature	S. A. Truca	Date Considered	2-13-06
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹Applicant's unique citation designation number (optional). ²See Kind Codes of USPTO Patent Documents at www.uspto.gov, MPEP 901.04 or in the comment box of this document. ³Enter Office that issued the document, by the two-letter code (WIPO Standard ST. 3). ⁴For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁶Applicant is to indicate here if English language Translation is attached.